Notice of Allowability	Application No.	Applicant(s)
	10/665,546	TAIRA, HIROSHI
	Examiner	Art Unit
	Geoffrey Mruk	2853
The MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this ap or other appropriate communication IGHTS. This application is subject t	plication. If not included n will be mailed in due course. THIS
1. This communication is responsive to <u>applicant's argument</u>	s dated 1 December 2006.	
2. The allowed claim(s) is/are <u>1-12</u> .		
 3. Acknowledgment is made of a claim for foreign priority una) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority do International Bureau (PCT Rule 17.2(a)). 	e been received. e been received in Application No	
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the requirements
4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which giv		
5. CORRECTED DRAWINGS (as "replacement sheets") mus	st be submitted.	•
(a) including changes required by the Notice of Draftspers	son's Patent Drawing Review (PTO	-948) attached
1) 🗌 hereto or 2) 🔲 to Paper No./Mail Date		
(b) including changes required by the attached Examiner' Paper No./Mail Date	's Amendment / Comment or in the (Office action of :
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in (
 DEPOSIT OF and/or INFORMATION about the depo- attached Examiner's comment regarding REQUIREMENT 		
Attachment(s)		
1. Notice of References Cited (PTO-892)	5. Notice of Informal F	
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	 Interview Summary Paper No./Mail Da 	ite
Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date	7. X Examiner's Amend	ment/Comment
4. Examiner's Comment Regarding Requirement for Deposit of Biological Material	 Examiner's Statem Other 	ent of Reasons for Allowance
	-	STEPHEN MEIER
	SUPER\	VISORY PATENT EXAMINER

EXAMINER'S COMMENT

The examiner makes of record that the applicant's arguments dated 1 December 2006 contains a typographical error. The foreign priority to Japanese patent application number JP 2002-278917 is incorrect. The correct foreign priority patent application number is JP 2002-278971. The examiner further notes that the English translation of JP 2002-278971 dated 1 December 2006 is the correct document.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Geoffrey Mruk whose telephone number is 571 272-2810. The examiner can normally be reached on 7am - 330pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Stephen Meier can be reached on 571 272-2149. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/665,546

Art Unit: 2853

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

GSM 1/12/2007

STEPHEN MEIER SUPERVISORY PATENT EXAMINER

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